Semiconductor Device Modeling & Circuit Simulation

LTP 313

UNIT-I

Compound Semiconductor, Lattice Structure, Carrier Drift, Direct & Indirect Semiconductors, Scattering, Recombination, Mean Life Time, Continuity Equation

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UNIT-II

PN Junction Characteristics, Current Component in Diode, Equivalent Circuit of Diode, BJT Characteristics, Second Order Effects in BJT: Thermal Run Away, Base Width Modulation, Kirk Effect, Band Gap Narrowing & Small Signal Analysis

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UNIT-III

Ebers-Moll Model, Hybrid Pi Model, Figure of Merit, Approximation & complete equivalent model of BJT, Charge Control Model, Gummel Poon Model, SPICE model of BJT & Simulation of BJT

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UNIT-IV

N- Channel & P-Channel MOS characteristic and feature, Enhancement and depletion mode, :Second order effect of MOS: Body Effect, Channel length modulation, Sub threshold conditions, DIBL, Hot carrier effect, Mobility degradation, Velocity saturation, CMOS latch up, MOS parasitic capacitances and resistance

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UNIT-V

Circuit models for MOSFET: Small Signal Model, BISM Model, SPICE Model, Simulation & Layout design DC, AC & Transient analysis of linear and non linear circuits, Logic & Timing Simulation

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Text Books:

- 1. Ben G. Streetman & Sanjay Banerjee, "Solid State Electronic Devices", Sixth Edition, Prentice Hall of India Private Limited, India.
- 2. Jacob Millman & Christos C. Halkias,, "Integrated Electronics", Second Edition, Tata McGraw Hill Publication, India.

- 3. Kannan Kanno, "Semiconductor Devices and Physics", Prentice Hall of India Private Limited, India.
- 4. Jan M. Rabaey, Anantha Chandrakasan and Borivoje Nikolic, "Digital Integrated Circuits", Second Edition, Prentice Hall of India Private Limited, India.
- 5. M.Rashid, "Introduction to PSpice",